


<b>Search Notes</b> 	<b>Application/Control No.</b> 10501857	<b>Applicant(s)/Patent Under Reexamination</b> MAJOR ET AL.
	<b>Examiner</b> ERIC YEN	<b>Art Unit</b> 2626

SEARCHED			
Class	Subclass	Date	Examiner
704	270-275	5/11/08	EY

SEARCH NOTES		
Search Notes	Date	Examiner
EAST Search (attached)	5/11/08	EY
EIC Search (attached)	5/11/08	EY

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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